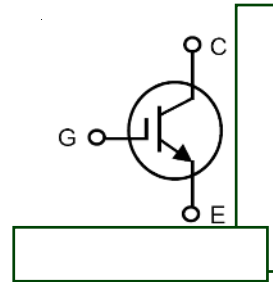


GenX3™ 600V IGBT

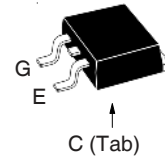
IXGA36N60A3
IXGP36N60A3
IXGH36N60A3

V_{CES} = 600V
I_{C110} = 36A
V_{CE(sat)} ≤ 1.4V

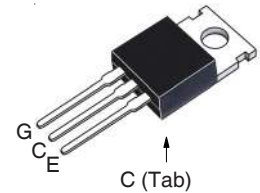
Ultra Low V_{sat} PT IGBT for up to 5kHz Switching



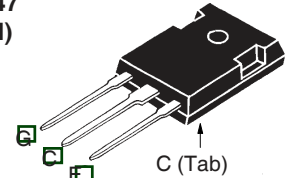
TO-263 (IXGA)



TO-220 (IXGP)



TO-247 (IXGH)



G = Gate C = Collector
 E = Emitter Tab = Collector

| Symbol | Test Conditions | Maximum Ratings | |
|-------------------|---|--|----------|
| V _{CES} | T _C = 25°C to 150°C | 600 | V |
| V _{CGR} | T _J = 25°C to 150°C, R _{GE} = 1MΩ | 600 | V |
| V _{GES} | Continuous | ± 20 | V |
| V _{GEM} | Transient | ± 30 | V |
| I _{C25} | T _C = 25°C | 96 | A |
| I _{C110} | T _C = 110°C | 36 | A |
| I _{CM} | T _C = 25°C, 1ms | 200 | A |
| SSOA (RBSOA) | V _{GE} = 15V, T _{VJ} = 125°C, R _G = 5Ω Clamped Inductive Load | I _{CM} = 60 V _{CE} ≤ V _{CES} | A |
| P _C | T _C = 25°C | 220 | W |
| T _J | | -55 ... +150 | °C |
| T _{JM} | | 150 | °C |
| T _{stg} | | -55 ... +150 | °C |
| T _L | Maximum Lead Temperature for Soldering | 300 | °C |
| T _{SOLD} | 1.6 mm (0.062in.) from Case for 10s | 260 | °C |
| F _C | Mounting Force (TO-263) | 10..65 / 2.2..14.6 | N/lb |
| M _d | Mounting Torque (TO-220 & TO-247) | 1.13 / 10 | Nm/lb.in |
| Weight | TO-263 | 2.5 | g |
| | TO-220 | 3.0 | g |
| | TO-247 | 6.0 | g |

Features

- Optimized for Low Conduction Losses
- Square RBSOA
- International Standard Packages

Advantages

- High Power Density
- Low Gate Drive Requirement

Applications

- Power Inverters
- UPS
- Motor Drives
- SMPS
- PFC Circuits
- Battery Chargers
- Welding Machines
- Lamp Ballasts
- Inrush Current Protection Circuits

| Symbol | Test Conditions (T _J = 25°C, Unless Otherwise Specified) | Characteristic Values | | |
|----------------------|---|-----------------------|------|-----------------|
| | | Min. | Typ. | Max. |
| BV _{CES} | I _C = 250μA, V _{GE} = 0V | 600 | | V |
| V _{GE(th)} | I _C = 250μA, V _{CE} = V _{GE} | 3.0 | | V |
| I _{CES} | V _{CE} = V _{CES} , V _{GE} = 0V T _J = 125°C | | | 25 μA 250 μA |
| I _{GES} | V _{CE} = 0V, V _{GE} = ±20V | | | ±100 nA |
| V _{CE(sat)} | I _C = 30A, V _{GE} = 15V, Note 1 | | | 1.4 V |

| Symbol | Test Conditions ($T_J = 25^\circ\text{C}$ Unless Otherwise Specified) | Characteristic Values | | |
|--------------|--|-----------------------|--------------------|------|
| | | Min. | Typ. | Max. |
| g_{fs} | $I_C = 30\text{A}, V_{CE} = 10\text{V}$, Note 1 | 25 | 42 | S |
| C_{ies} | $V_{CE} = 25\text{V}, V_{GE} = 0\text{V}, f = 1\text{MHz}$ | | 2380 | pF |
| C_{oes} | | | 115 | pF |
| C_{res} | | | 30 | pF |
| Q_g | $I_C = 30\text{A}, V_{GE} = 15\text{V}, V_{CE} = 0.5 \cdot V_{CES}$ | | 80 | nC |
| Q_{ge} | | | 12 | nC |
| Q_{gc} | | | 36 | nC |
| $t_{d(on)}$ | Inductive load, $T_J = 25^\circ\text{C}$ $I_C = 30\text{A}, V_{GE} = 15\text{V}$ $V_{CE} = 400\text{V}, R_G = 5\Omega$ Note 2 | | 18 | ns |
| t_{ri} | | | 23 | ns |
| E_{on} | | | 0.74 | mJ |
| $t_{d(off)}$ | | | 330 | ns |
| t_{fi} | | | 325 | ns |
| E_{off} | | | 3.00 | mJ |
| R_{thJC} | | | | |
| R_{thCS} | TO-220 | 0.50 | $^\circ\text{C/W}$ | |
| | TO-247 | 0.21 | $^\circ\text{C/W}$ | |

Notes:

1. Pulse test, $t \leq 300\mu\text{s}$, duty cycle, $d \leq 2\%$.
2. Switching times & energy losses may increase for higher V_{CE} (clamp), T_J or R_G .

IXYS Reserves the Right to Change Limits, Test Conditions and Dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:

| | | | | | | | | | |
|-----------|-----------|-----------|-----------|--------------|--------------|--------------|--------------|--------------|-------------|
| 4,835,592 | 4,931,844 | 5,049,961 | 5,237,481 | 6,162,665 | 6,404,065 B1 | 6,683,344 | 6,727,585 | 7,005,734 B2 | 7,157,338B2 |
| 4,860,072 | 5,017,508 | 5,063,307 | 5,381,025 | 6,259,123 B1 | 6,534,343 | 6,710,405 B2 | 6,759,692 | 7,063,975 B2 | |
| 4,881,106 | 5,034,796 | 5,187,117 | 5,486,715 | 6,306,728 B1 | 6,583,505 | 6,710,463 | 6,771,478 B2 | 7,071,537 | |

Fig. 1. Output Characteristics @ $T_J = 25^\circ\text{C}$

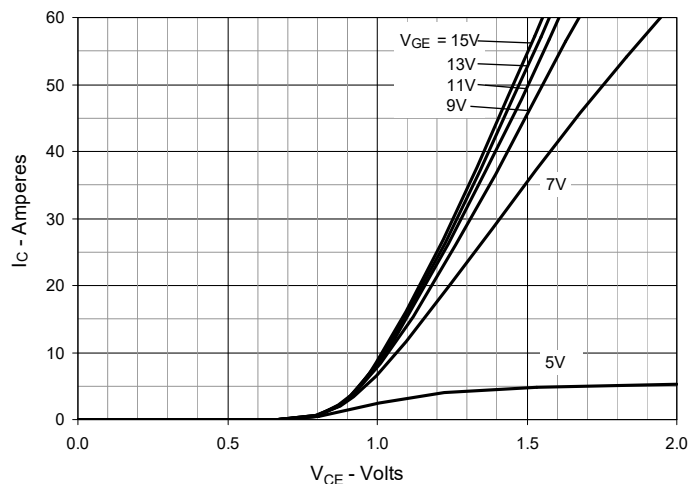


Fig. 2. Extended Output Characteristics @ $T_J = 25^\circ\text{C}$

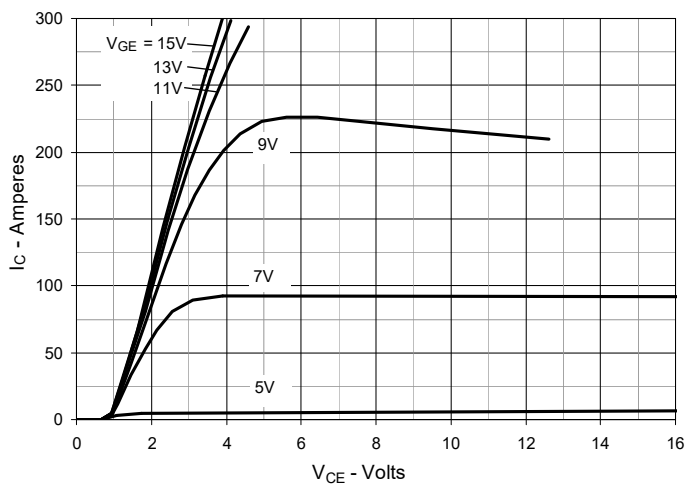


Fig. 3. Output Characteristics @ $T_J = 125^\circ\text{C}$

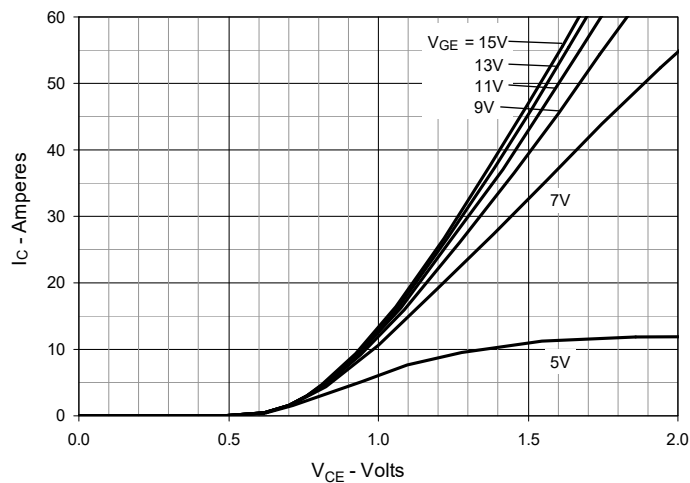


Fig. 4. Dependence of $V_{CE(sat)}$ on Junction Temperature

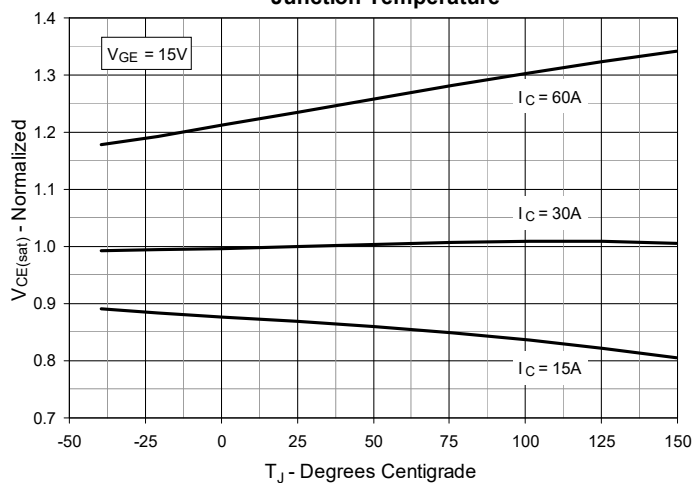


Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage

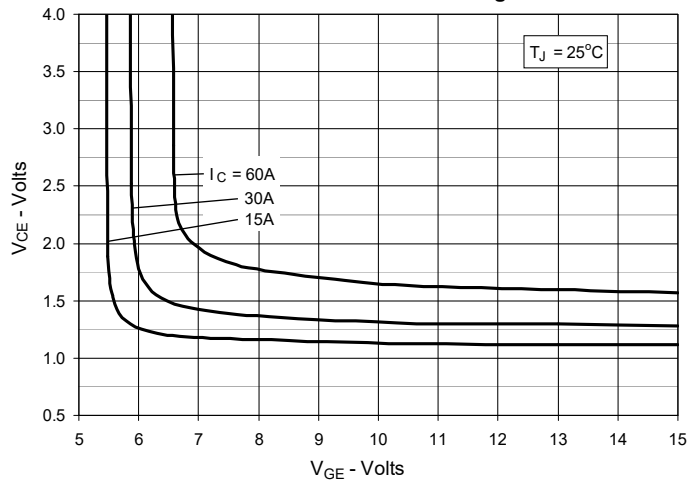


Fig. 6. Input Admittance

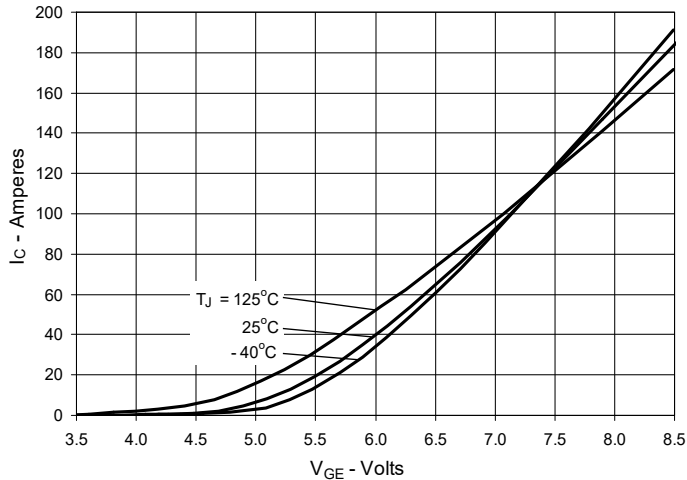


Fig. 7. Transconductance

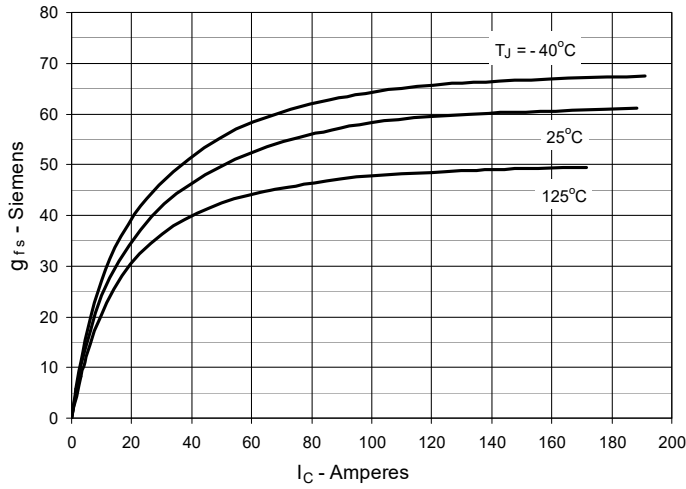


Fig. 8. Gate Charge

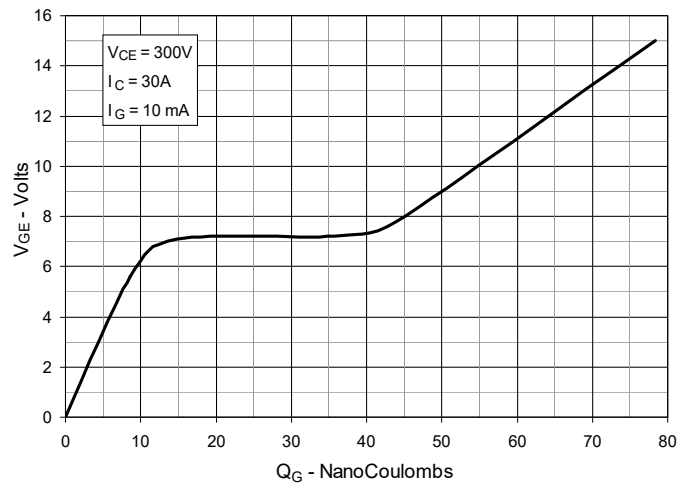


Fig. 9. Reverse-Bias Safe Operating Area

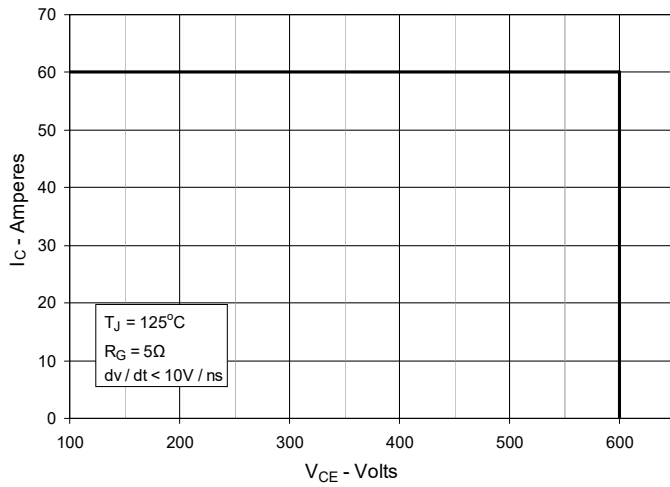


Fig. 10. Capacitance

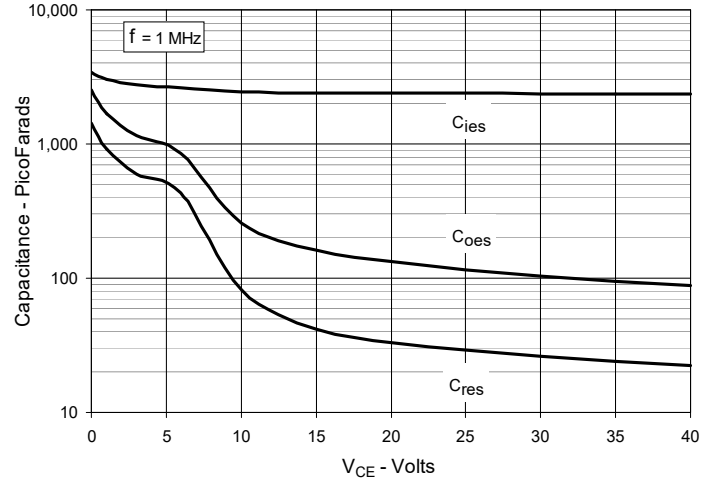


Fig. 11. Maximum Transient Thermal Impedance

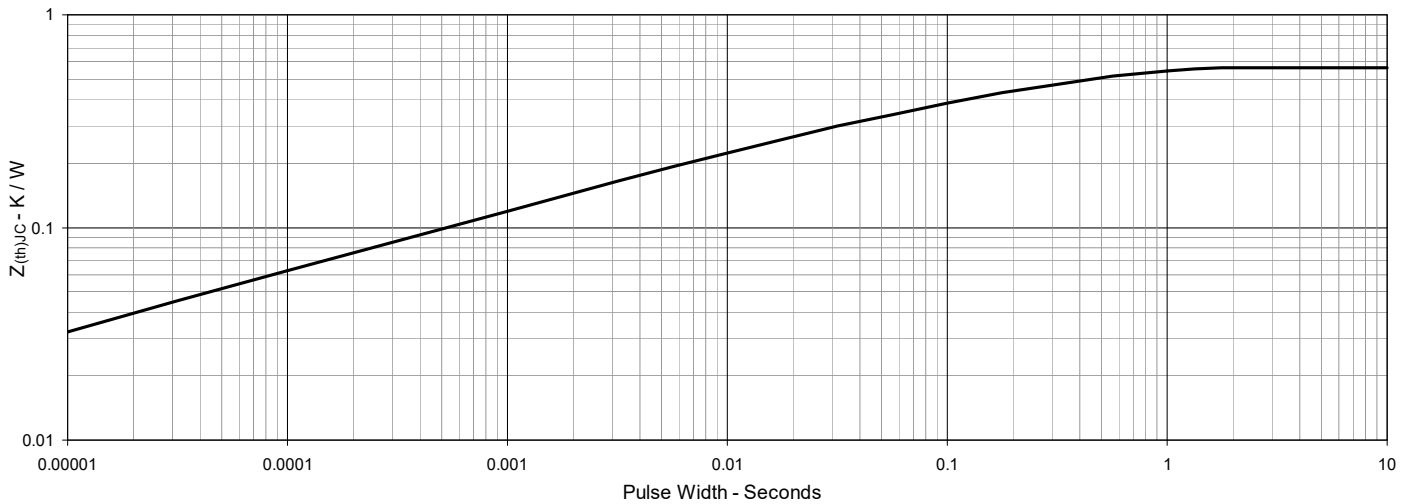


Fig. 12. Inductive Switching Energy Loss vs. Gate Resistance

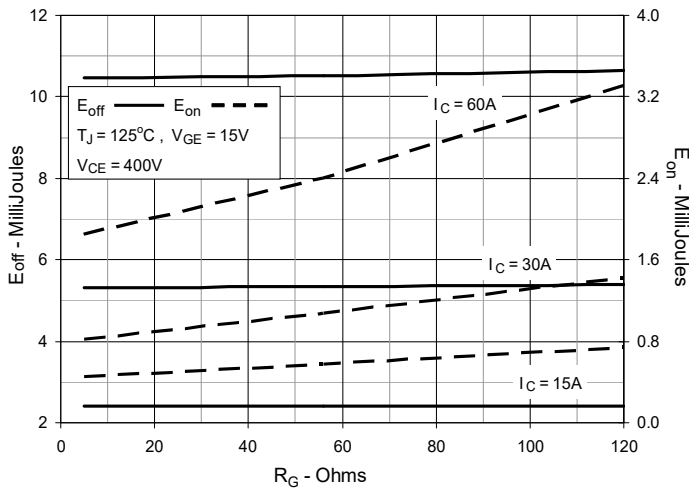


Fig. 13. Inductive Switching Energy Loss vs. Junction Temperature

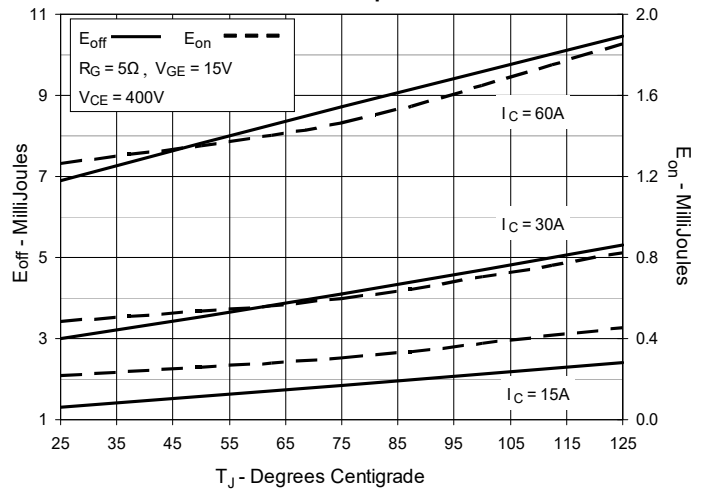


Fig. 14. Inductive Switching Energy Loss vs. Collector Current

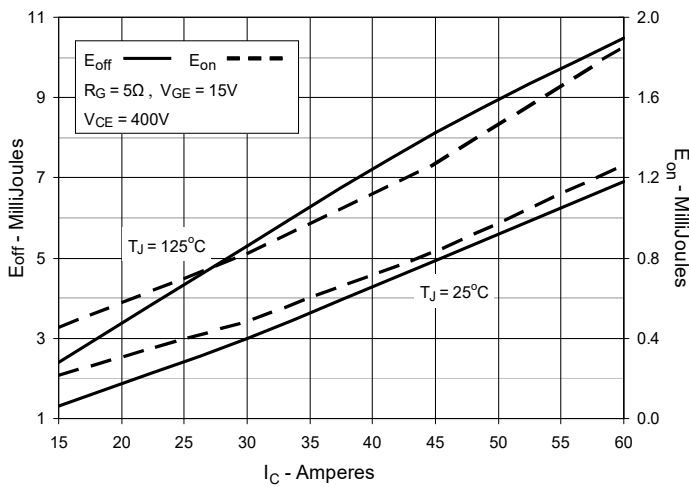


Fig. 15. Inductive Turn-off Switching Times vs. Gate Resistance

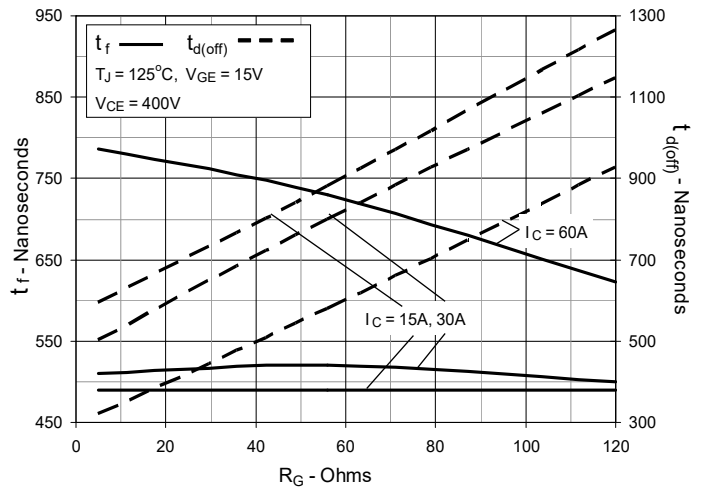


Fig. 16. Inductive Turn-off Switching Times vs. Collector Current

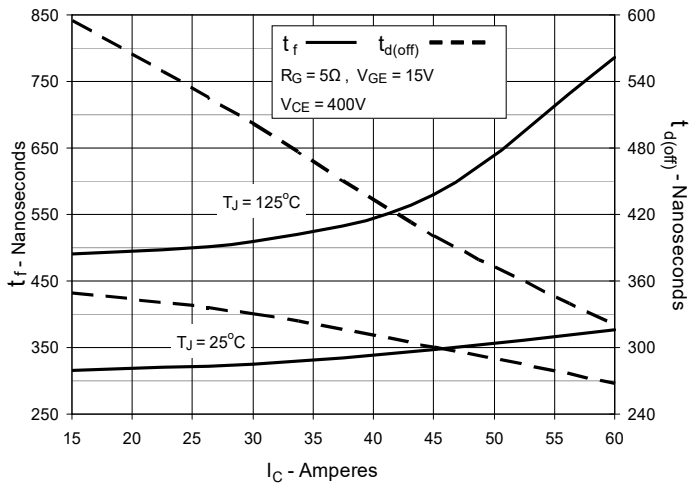


Fig. 17. Inductive Turn-off Switching Times vs. Junction Temperature

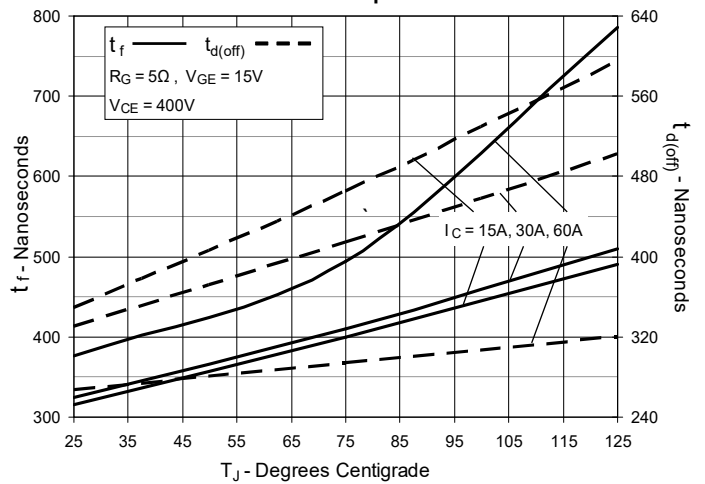


Fig. 18. Inductive Turn-on Switching Times vs. Gate Resistance

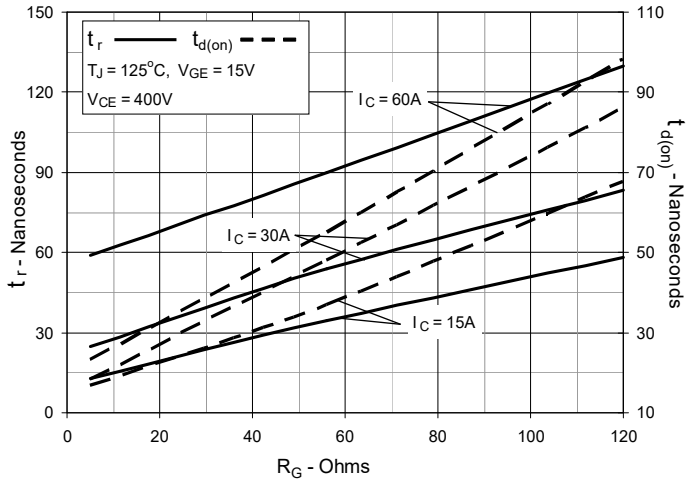


Fig. 19. Inductive Turn-on Switching Times vs. Junction Temperature

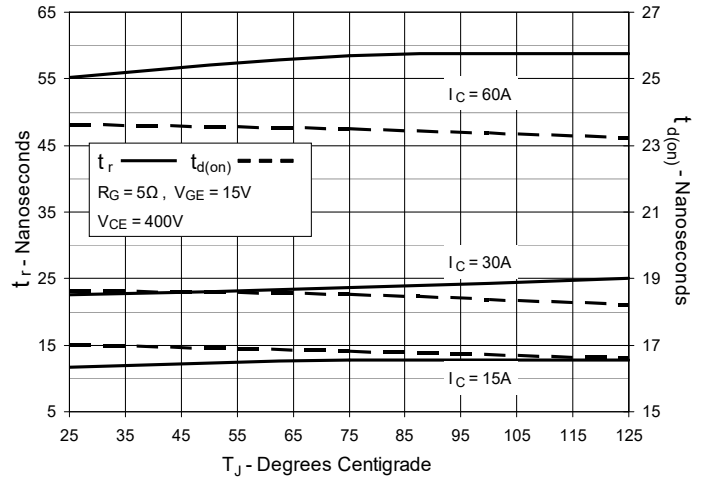


Fig. 20. Inductive Turn-on Switching Times vs. Collector Current

